## **Supporting Information for**

## Manipulation of ionized impurity scattering for achieving high thermoelectric performance in n-type Mg<sub>3</sub>Sb<sub>2</sub>-based materials

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- 1. Thermoelectric properties of  $Mg_{3.1}T_{0.1}Sb_{1.5}Bi_{0.49}Te_{0.01}$  (T = W, Ni, Mo, V, and Zn)
- 2. XRD of  $Mg_{3.1}A_{0.1}Sb_{1.5}Bi_{0.49}Te_{0.01}$  (A = Fe, Co, Hf, and Ta)
- 3. XRD of Mg<sub>3.2-x</sub>Co<sub>x</sub>Sb<sub>1.5</sub>Bi<sub>0.5-x</sub>Te<sub>x</sub> (x = 0, 0.025, 0.05, 0.075, and 0.1)
- 4. Thermoelectric properties of  $Mg_{3,2-x}Co_xSb_{1,5}Bi_{0,49}Te_{0,01}$
- 5. Hall measurement of  $Mg_{3.2}Sb_{1.5}Bi_{0.49}Te_{0.01}$
- 6. Rietveld refinement of neutron powder diffraction
- 7. Calculated dielectric constant for Mg<sub>3</sub>Sb<sub>2</sub> and Mg<sub>3</sub>Sb<sub>1.5</sub>Bi<sub>0.5</sub>
- 8. Densities of  $Mg_{3.2}Sb_{1.5}Bi_{0.49}Te_{0.01}$  and  $Mg_{3.1}A_{0.1}Sb_{1.5}Bi_{0.49}Te_{0.01}$  (*A* = Fe, Co, Hf, and Ta)
- 9. Specific heat and thermal diffusivities of  $Mg_{3.2}Sb_{1.5}Bi_{0.49}Te_{0.01}$  and  $Mg_{3.1}A_{0.1}Sb_{1.5}Bi_{0.49}Te_{0.01}$  (A = Fe, Co, Hf, and Ta)
- 10. Repeated measurement of electrical resistivity



Figure S1. Thermoelectric properties of  $Mg_{3.1}T_{0.1}Sb_{1.5}Bi_{0.49}Te_{0.01}$  (T = W, Ni, Mo, V, Zn). (a) Electrical conductivity, (b) temperature exponent of electrical conductivity, (c) Seebeck coefficient, (d) power factor, (e) thermal conductivity, and (f) ZT.



Figure S2. XRD patterns of  $Mg_{3.2}A_{0.1}Sb_{1.5}Bi_{0.49}Te_{0.01}$  (A = Fe, Co, Hf, and Ta).



Figure S3. XRD patterns of  $Mg_{3,2-x}Co_xSb_{1.5}Bi_{0.49}Te_{0.01}$  (*x* = 0, 0.025, 0.05, 0.075, and 0.1).



Figure S4. (a) Temperature-dependent electrical conductivity of, (b) relationship between the temperature exponent and composition for, (c) Seebeck coefficient of, and (d) *PF* of Mg<sub>3.2-x</sub>Co<sub>x</sub>Sb<sub>1.5</sub>Bi<sub>0.49</sub>Te<sub>0.01</sub> (x = 0, 0.025, 0.05, 0.075, and 0.1).



Figure S5. (a) Temperature-dependent thermal conductivity and (b) ZT of  $Mg_{3.2-x}Co_xSb_{1.5}Bi_{0.49}Te_{0.01}$  (x = 0, 0.025, 0.05, 0.075, and 0.1). (c) Calculated (ZT)<sub>eng</sub> at  $T_C = 323$  K and  $T_H = 773$  K and (d) comparison of (ZT)<sub>avg</sub> among  $Mg_{3.2}Sb_{1.5}Bi_{0.49}Te_{0.01}$  and  $Mg_{3.2-x}Co_xSb_{1.5}Bi_{0.49}Te_{0.01}$ .



Figure S6. Repeated Hall measurements of Mg<sub>3.2</sub>Sb<sub>1.5</sub>Bi<sub>0.49</sub>Te<sub>0.01</sub> during the heating and cooling cycles.



Figure S7. Rietveld refinement of neutron diffraction for (a)  $Mg_{3.2}Sb_{1.5}Bi_{0.49}Te_{0.01}$  and (b)  $Mg_{3.1}Co_{0.1}Sb_{1.5}Bi_{0.49}Te_{0.01}$ .

The appearance of unknown impurity peaks in the samples prepared for neutron powder diffraction meant some assumptions had to be made to reach a stable, converging refinement. The first assumption made was that the Mg1 site (1/3, 2/3, z) was fully occupied for both the undoped and doped samples. This site often overfilled when refinement was attempted. The isotropic displacement parameters ( $B_{iso}$ ) found

during refinement of the undoped sample were used and fixed during refinement of the doped sample. Additionally, the Co occupancy was fixed based on the formula,  $Mg_{3.1}Co_{0.1}Sb_{1.5}Bi_{0.49}Te_{0.01}$ . Based on the assumption that the Mg1 site was fully occupied, the Co was placed on the Mg2 site (0, 0, 0). Attempts to refine more parameters than those reported often yielded physically unreasonable values for the isotropic displacement parameters and occupations. It is possible that without the presence of impurities, a more in-depth refinement could be performed, which could yield different results.

	$Mg_{3,2}Sb_{1,5}Bi_{0,49}Te_{0,01}$	Te <sub>0.01</sub> $Mg_{3.1}Co_{0.1}Sb_{1.5}Bi_{0.49}Te_{0.01}$	
Rp	25.0	29.5	
Rwp	23.9	30.1	
Re	12.5	12.2	
Chi2	3.684	6.106	
а	4.5755(4) Å	4.5711(5) Å	
С	7.2626(8) Å	7.261(1) Å	
Mg1 z	0.6292(7)	0.6236(9)	
Sb/Bi/Te z	0.2310(7)	0.2310(10)	
B <sub>iso</sub> Mg1	$1.6 \text{ Å}^2$	$1.6 \text{ Å}^2$	
B <sub>iso</sub> Mg2	$1.2 \text{ Å}^2$	1.2 Å <sup>2</sup>	
B <sub>iso</sub> Sb/Bi/Te	$1.2 \text{ Å}^2$	$1.2 \text{ Å}^2$	
Mg2 occupation	$89\% \pm 2\%$	91% ± 2%	

Table S1. Detailed results for the refinement of  $Mg_{3,2}Sb_{1,5}Bi_{0,49}Te_{0,01}$  and  $Mg_{3,1}Co_{0,1}Sb_{1,5}Bi_{0,49}Te_{0,01}$ .

Material	Contributions	xx	уу	ZZ
$Mg_3Sb_2$	electronic	13.8	13.8	16.4
	ionic	16.3	16.3	17.3
$Mg_3Sb_{1.5}Bi_{0.5}$	electronic	15.4	15.1	18.1
	ionic	17.3	16.9	18.1

Table S2. Calculated dielectric constant for Mg<sub>3</sub>Sb<sub>2</sub> and Mg<sub>3</sub>Sb<sub>1.5</sub>Bi<sub>0.5</sub>

Table S3. Densities of  $Mg_{3.2}Sb_{1.5}Bi_{0.49}Te_{0.01}$  and  $Mg_{3.1}A_{0.1}Sb_{1.5}Bi_{0.49}Te_{0.01}$  (*A* = Fe, Co, Hf, and Ta).

Specimen	Density (g cm <sup>-3</sup> )	
Mg <sub>3.2</sub> Sb <sub>1.5</sub> Bi <sub>0.49</sub> Te <sub>0.01</sub>	4.41	
$Mg_{3.1}Fe_{0.1}Sb_{1.5}Bi_{0.49}Te_{0.01}$	4.40	
$Mg_{3.1}Co_{0.1}Sb_{1.5}Bi_{0.49}Te_{0.01}$	4.41	
$Mg_{3.1}Hf_{0.1}Sb_{1.5}Bi_{0.49}Te_{0.01}$	4.54	
$Mg_{3.1}Ta_{0.1}Sb_{1.5}Bi_{0.49}Te_{0.01}$	4.33	



Figure S8. Thermal diffusivities and specific heat of  $Mg_{3.2}Sb_{1.5}Bi_{0.49}Te_{0.01}$  and  $Mg_{3.1}A_{0.1}Sb_{1.5}Bi_{0.49}Te_{0.01}$  (A = Fe, Co, Hf, and Ta).



Figure S9. Electrical resistivity of  $Mg_{3.2}Sb_{1.5}Bi_{0.49}Te_{0.01}$  and  $Mg_{3.1}Ta_{0.1}Sb_{1.5}Bi_{0.49}Te_{0.01}$  during heating and cooling cycles.